

**Search Notes**

Application/Control No.

10/784,151

Examiner

Lois Zheng

Applicant(s)/Patent under  
Reexamination

FUKUNAGA ET AL.

Art Unit

1742

**SEARCHED**

Class	Subclass	Date	Examiner
204	196.02	1/4/2007	LLZ
204	196.06	1/4/2007	LLZ
204	228.6	1/4/2007	LLZ
205	101	1/4/2007	LLZ
205	291	1/4/2007	LLZ
210	656	1/4/2007	LLZ
356	337	1/4/2007	LLZ

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventorship Search	1/4/2007	LLZ
EAST search	1/4/2007	LLZ